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# VUE 250-P SCANNING ACOUSTIC MICROSCOPE

### Semiconductor Package Failure Analysis voids · disbonds · cracks · delamination · internal defects

**Customer Interface** Dual 22" HD LED Monitors

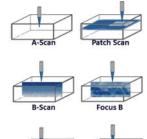
**Fixtures Open Tank Bed** 

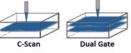
Instrumentation **Digital Pulser Receiver** Digitizer (Max 4 GHz)

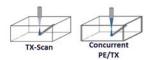
**User Experience Elements** HD LED Lighting ESD or Stainless Steel Tank

Maintenance Free Scan Axis Motor: Max Velocity: Accuracy & Repeatability:	Linear Servo 500 mm/s +/- 1.0 micron
Scan Envelope:	250 mm
Low Maintenance Step Axis: Step Envelope	125 mm
Low Maintenance Focus Axis: Focus Envelope	25 mm

**Dimensions:** 71.12 cm x 60.96 cm x 45.72 cm (W/D/H) 81 kg









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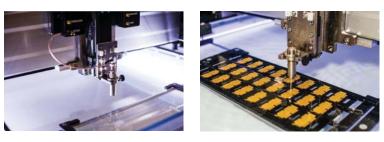


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## VUE 250-P SCANNING ACOUSTIC MICROSCOPE

#### **Included Software Modes:**

- Basic (user friendly)
- Advanced (detailed analysis)
- Production (automated scanning)
- Off-line Analysis (virtual scanning)



## **OKOS Digital Imaging System (ODIS)**



VUE 250-P imaging power surpasses modern standards delivering premium FA Lab features to semiconductor fabrication facilities. ODIS is the latest Acoustic Microscopy software with rich technical content built on current platforms and industry feedback. It includes both time domain and frequency domain imaging in real-time. Advanced analysis is provided through quantitative tools for measurement and classification of parts.

The Analysis version of ODIS allows non-scanning computers to virtually scan, view, and analyze data for simultaneous real-time analysis or post collection review. Supplied with your choice of Windows 7 or 10.

**Application Specific Transducers** 

for the highest quality resolution. Multiple transducer design for enhanced scan capability.

Cou	Inter	feit	t D	etection	· Pro	duct	Inspe	ction
_		_			_		_	

Product Reliability

3D Imaging

C-scan with Multi-gate SALI & SALI Groups

> Frequency Domain Imaging (FFT)

> > Advanced Time-of-Flight & Thickness Measurements

Real-time A-scan & A-scan Capture

- Process Validation
- · Quality Control
- Failure Analysis
- · Vendor Qualification · R&D
  - Void Gating (real-time) Cluster Analysis (post processing)





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